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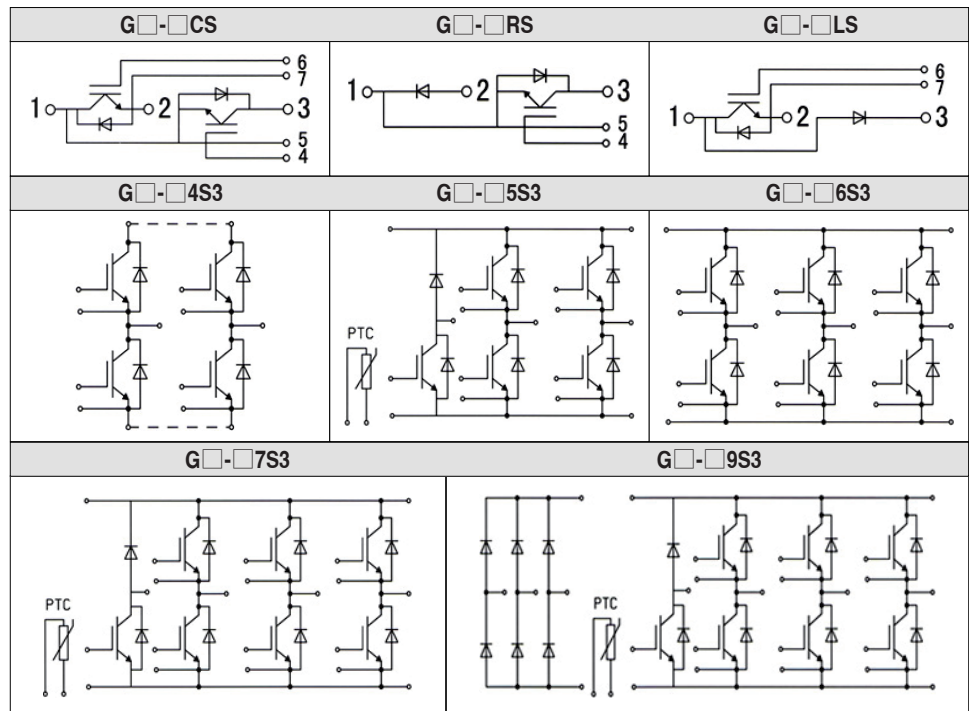
Characteristics

- SPT chip (soft-punch-through)
- MOS input control
- Ultrathin IGBT chip, great current low loss, low tail current
- Low VCE (sat) saturated voltage, positive temperature coefficient at high temperature
- High switch frequency, low switch loss
- High SC resistive ability
- Module creepage long distance design
- DBC insulated voltage above 2500VRMS

Typical Applications

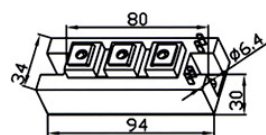
- AC and DC electric motor control
- Frequency transformer
- UPS
- Industry calefaction power supply
- Electric welding machine

Internal structure

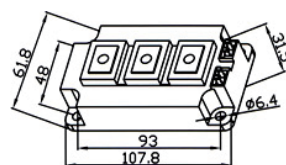


Major parameters

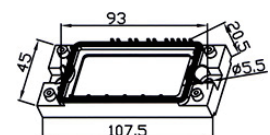
Parameters	Collector current Ic (A)					Vces(v) Collector-Emitter Voltage
	50,75,100,145	150,200,300,400	10,15,25,40	25,50	50,75	
Model	G□-□CS	G□-□CS	G□-□4S3	G□-□4S3	G□-□4S3	600,1200,1700
	G□-□RS	G□-□RS	G□-□5S3	G□-□5S3	G□-□6S3	
	G□-□LS	G□-□LS	G□-□6S3	G□-□6S3		
			G□-□7S3	G□-□7S3		
			G□-□9S3			
Exterior	Figure 1	Figure 2	Figure 3			



①



②



③

Characteristic

- SPT:Soft-punch-through technology
- VCE(sat)with positivetemperature coefficient
- Lower on-state and switching loss
- Hight short circuit capability
- “vacuum+H2+H” process gasatmosphere,Nearly voidlessoldering results1234567

650-12CS1 Technical details

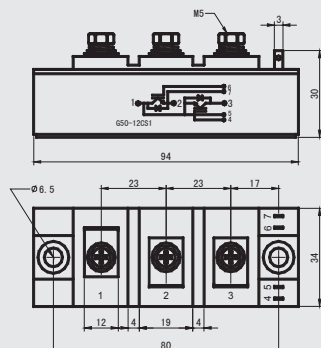
Characteristic values

	Symbol	Conditions	values	Unit
IGBT				
Collector-emitter voltage	V _{CES}		1200	V
DC-collector current	I _C	T _c =25(85)°C	75(50)	A
repetitive peak voltage	I _{CRM}	T _c =25(80)°C, tp=1ms	150(100)	A
gate-emitter peak voltage	V _{GES}		±20	V
operation temperature	T _{vj}		-40~+125	°C
storage temperature	T _{stg}		-40~+150	°C
insulation test voltage	V _{ISOL}	RMS, 1min, 50Hz	2500	V
Inverse diode				
DC-forward current	I _F	T _c =25(80)°C	75 (50)	A
repetitive peak forward voltage	I _{FRM}	T _c =25(80)°C, tp=1ms	150 (100)	A
forward surge current	I _{FSM}	tp=10ms, sin, T _j =150°C	500	A

Characteristic values

Paramiter	Symbol	Conditions	values			IGBT
			typ.	typ.	max.	
IGBT						
gate threshold voltage	V _{GE(th)}	V _{GE} =V _{CE} , I _c =2mA, T _j =25°C	4.5	5.5	6.5	V
collector-emitter cut-off current	I _{CES}	V _{GE} =0V, V _{CE} =V _{CES} , T _j =25(125)°C		0.1	0.3	mA
gate-leakage current	I _{GES}	V _{GE} =0V, V _{GE} =20V, T _j =25°C	-200		200	nA
collector-emitter threshold voltage	V _{CE (TO)}	T _j =25 (125)°C		1(0.9)	1.15(1.05)	V
collector-emitter threshold voltage	r _{CE}	V _{GE} =15V, T _j =25 (125)°C		18(24)	24(30)	mΩ
collector-emitter saturation vottage	V _{CE(SAT)}	I _c =50A, V _{GE} =15V, chip level		1.9 (2.1)	2.35 (2.55)	V
input capacitance	C _{ies}	V _{GE} =0, V _{CE} =25V, f=1MHZ		4.5		nF
output capacitance	C _{oes}			0.6		nF
Reverse transfer capacitance	C _{res}			0.55		nF
stray inductance module	L _{CE}				25	nH
module lead resistance	R _{CC+EE'}	terminals-chip, T _c =25 (125)°C	0.75 (1)			mΩ
Short circuit current	I _{sc}	tp _{sc} ≤1s, V _{GE} =15V, T _{vj} =125°C, V _{CC} =900V, V _{CEM} ≤1200V	280			A
turen on delay time	t _{d (on)}	V _{CC} =600V, I _c =50A	90			ns
rise time	t _r	R _{gon} =R _{goff} =15	55			ns
turn off delay time	t _{d (off)}	T _j =125°C, V _{GE} =±15V	440			ns
fall time	t _f		40			ns
turn-on energy loss per pules	E _{on}		5.7			mJ
turn-off energy loss per pulse	E _{off}		4.7			mJ
Inverse diode						
forward voltage	V _F	I _F =50A, V _{GE} =0V; T _j =25(125)°C	2(1.8)			V
threshold vottage of diode	V _(TO)	T _j =25(125)°C	1.1			V
peak reverse recovery current	I _{RRM}	I _F =50A, V _{GE} =0, diF/dt=900A/us,	40			A
Reverse recovered time	t _{rr}	T _j =125, V _R =600V	400			nS
Thermal properties						
Thermal resistance, junction to case	R _{th(j-c)}	per IGBT	0.3			K/W
	R _{th(j-c)D}	per inverse diode	0.65			K/W
Thermal resistance, case to heat sink	R _{th(c-s)}	per module	0.05			K/W
Mechanical properties						
mounting torque	M1	M6	3		5	NM
terminal connection tord	M2	M5	2.5		5	NM
weight	MAX	176				g
Case color		white				K/W
Dimensions	MAX	94x3430.5				mm

Dimensions



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Characteristic

- SPT:Soft-punch-through technology
- VCE(sat)with positivetemperature coefficient
- Lower on-state and switching loss
- High short circuit capability
- "vacuum+H2+H" process gasatmosphere,Nearly voidlessoldering results1234567

G75-12CS1 Technical Details

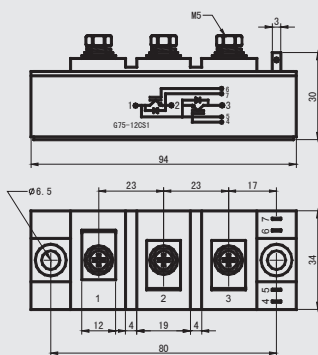
Maximum rated values

	Symbol	Conditions	values	Unit
IGBT				
Collector-emitter voltage	VCES		1200	V
DC-collector current	IC	Tc=25(85)°C	75(50)	A
repetitive peak voltage	ICRM	Tc=25(80)°C, tp=1ms	200(150)	A
gate-emitter peak voltage	VGES		± 20	V
operation temperature	Tvj		-40~+125	°C
storage temperature	Tstg		-40~+150	°C
insulation test voltage	VISOL	RMS, 1min, 50Hz	2500	V
Inverse diode				
DC-forward current	IF	Tc=25(80)°C	100 (75)	A
repetitive peak forward voltage	IFRM	Tc=25(80)°C, tp=1ms	200 (150)	A
forward surge current	IFSM	tp=10ms, sin, Tj=150°C	700	A

Characteristic values

Paramiter	Symbol	Conditions	values			IGBT
			typ.	typ.	max.	
IGBT						
gate threshold voltage	VGE(th)	VGE=VCE, Ic=3mA, Tj=25°C	4.5	5.5	6.5	V
collector-emitter cut-off current	ICES	VGE=0V, Vce=VCES, Tj=25(125)°C		0.1	0.3	mA
gate-leakage current	IGES	VGE=0V, VGE=20V, Tj=25°C	-200		200	nA
collector-emitter threshold voltage	VCE (TO)	Tj=25 (125)°C		1(0.9)	1.15(1.05)	V
collector-emitter threshold voltage	rCE	VGE=15V, Tj=25 (125)°C	13(16)		16(20)	mΩ
collector-emitter saturation vottage	VCE(SAT)	Ic=75 A, VGE=15V, chip level	1.9 (2.1)		2.35 (2.55)	V
input capacitance	Cies	VGE=0, VCE=25V, f=1MHZ		6.2		nF
output capacitance	Coes			0.74		nF
Reverse transfer capacitance	Cres			0.71		nF
stray inductance module	LCE				25	nH
module lead resistance	RCC'+EE'	terminals-chip, Tc=25 (125)°C	0.75 (1)			mΩ
Short circuit current	Isc	tpsc≤10s, VGE=15V, TVj=125°C, VCC=900V, VCEM≤1200V	420			A
turen on delay time	td (on)	VCC=600V, Ic=70A	150			ns
rise time	tr	Rgon=Rgoff=12	45			ns
turn off delay time	td (off)	Tj=125°C, VGE=± 15V	560			ns
fall time	tf		50			ns
turn-on energy loss per pules	Eon		8.5			mj
turn-off energy loss per pulse	Eoff		7.5			mj
Inverse diode						
forward voltage	VF	If=75A, VGE=0V; Tj=25(125)°C		2(1.8)	2.5(1.9)	V
threshold voltage of diode	V(TO)	Tj=25(125)°C		1.1	1.2	V
peak reverse recovery current	Irrm	If=75A, VGE=0, diF/dt=600A/us,	62			A
Reverse recovered time	trr	Tj=125, Vr=600V	200			nS
Thermal properties						
Thermal resistance, junction to case	Rth(j-c)	per IGBT	0.2			K/W
	Rth(j-c)D	per inverse diode	0.5			K/W
Thermal resistance, case to heat sink	Rth(c-s)	per module	0.05			K/W
Mechanical properties						
mounting torque	M1	M6	3		5	NM
terminal connection tord	M2	M5	2.5		5	NM
weight	MAX	176				g
Case color		white				K/W
Dimensions	MAX	94x3430.5				mm

Dimensions



Characteristic

- SPT:Soft-punch-through technology
- VCE(sat)with positive temperature coefficient
- Lower on-state and switching loss
- High short circuit capability
- “vacuum+H2+H” process

G100-12CS1 Technical Details

Maximum rated values

	Symbol	Conditions	values	Unit
IGBT				
Collector-emitter voltage	V _{CEs}		1200	V
DC-collector current	I _C	T _c =25(85)°C	150(100)	A
repetitive peak voltage	I _{CRM}	T _c =25(80)°C, tp=1ms	300(200)	A
gate-emitter peak voltage	V _{GES}		±20	V
operation temperature	T _{vj}		-40~+125	°C
storage temperature	T _{stg}		-40~+150	°C
insulation test voltage	V _{ISOL}	RMS, 1min, 50Hz	2500	V
Inverse diode				
DC-forward current	I _F	T _c =25(80)°C	150 (95)	A
repetitive peak forward voltage	I _{FRM}	T _c =25(80)°C, tp=1ms	300 (190)	A
forward surge current	I _{FSM}	tp=10ms, sin, T _j =150°C	1000	A

Characteristic values

Parameter	Symbol	Conditions	values			IGBT
			typ.	typ.	max.	
IGBT						
gate threshold voltage	V _{GE(th)}	V _{GE} =V _{CE} , I _c =4mA, T _j =25° C	4.5	5.5	6.5	V
collector-emitter cut-off current	I _{CEs}	V _{GE} =0V, V _{CE} =V _{CEs} , T _j =25(125)°C		0.1	0.3	mA
gate-leakage current	I _{GES}	V _{GE} =0V, V _{GE} =20V, T _j =25° C	-200		200	nA
collector-emitter threshold voltage	V _{CE (TO)}	T _j =25 (125)°C	1(0.9)		1.15(1.05)	V
collector-emitter threshold voltage	r _{CE}	V _{GE} =15V, T _j =25 (125)°C	9(12)		12(15)	mΩ
collector-emitter saturation vottage	V _{CE(SAT)}	I _c =75 A, V _{GE} =15V, chip level	1.9 (2.1)		2.35 (2.55)	V
input capacitance	C _{ies}	V _{GE} =0, V _{CE} =25V, f=1MHZ		9		nF
output capacitance	C _{oes}			1		nF
Reverse transfer capacitance	C _{res}			1		nF
stray inductance module	L _{CE}				25	nH
module lead resistance	R _{CC'+EE'}	terminals-chip, T _c =25 (125)°C	0.75 (1)			mΩ
Short circuit current	I _{sc}	tp _{sc} ≤10s, V _{GE} =15V, T _{vj} =125° C, V _{CC} =900V, V _{CEM} ≤1200V	470			A
turen on delay time	t _{d (on)}	V _{CC} =600V, I _c =100A	190			ns
rise time	t _r	R _{gon} =R _{goff} =12	50			ns
turn off delay time	t _{d (off)}	T _j =125° C, V _{GE} =± 15V	590			ns
fall time	t _f		50			ns
turn-on energy loss per pules	E _{on}		11.5			mj
turn-off energy loss per pulse	E _{off}		9.5			mj
Inverse diode						
forward voltage	V _F	I _F =100A, V _{GE} =0V; T _j =25(125)°C		2.3(1.9)	2.55(2.0)	V
threshold voltage of diode	V _(TO)	T _j =25(125)°C		1.1	1.2	V
peak reverse recovery current	I _{RRM}	I _F =100A, V _{GE} =0, diF/dt=600A/us,	62			A
Reverse recovered time	t _{rr}	T _j =125, V _R =600V	200			nS
Thermal properties						
Thermal resistance, junction to case	R _{th(j-c)}	per IGBT	0.17			K/W
	R _{th(j-c)D}	per inverse diode	0.45			K/W
Thermal resistance, case to heat sink	R _{th(c-s)}	per module	0.05			K/W
Mechanical properties						
mounting torque	M1	M6	3		5	NM
terminal connection tord	M2	M5	2.5		5	NM
weight	MAX	176				g
Case color		white				K/W
Dimensions	MAX	94x3430.5				mm

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